L Number	Hits	Search Text	DB	Time stamp
1	2307	(("382/141-151") or ("348/87,126") or ("356/237.4,237.5")).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2001/10/02 14:07
8	24	gain near2 offset and ((("382/141-151") or ("348/87,126") or ("356/237.4,237.5")).CCLS.)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2001/10/02 14:15
15	5	gain with offset and ((("382/141-151") or ("348/87,126") or ("356/237.4,237.5")).CCLS.) not (gain near2 offset and ((("382/141-151") or ("348/87,126") or ("356/237.4,237.5")).CCLS.))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2001/10/02 14:16
22	6	gain same offset and ((("382/141-151") or ("348/87,126") or ("356/237.4,237.5")).CCLS.) not (gain near2 offset and ((("382/141-151") or ("348/87,126") or ("356/237.4,237.5")).CCLS.)) not (gain with offset and ((("382/141-151") or ("348/87,126") or ("356/237.4,237.5")).CCLS.) not (gain near2 offset and ((("382/141-151") or ("348/87,126") or ("356/237.4,237.5")).CCLS.)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2001/10/02 14:19
29	4	wafer with (resist or photoresist) with transparent with flat	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2001/10/02 14:22
36	177	wafer with transparent near film	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2001/10/02 14:31
43	3	("5045417").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2001/10/02 14:37
50	2	wafer near inspect$3 with (resist or photoresist) with transparent	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2001/10/02 14:44
57	80	wafer near (film or coat$3) with transparent	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2001/10/02 14:45
64	16	(wafer near (film or coat$3) with transparent) and inspect$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2001/10/02 14:58
71	216	(chip near2 chip) with inspect$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2001/10/02 14:58
78	142	(die near2 die) with inspect$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2001/10/02 15:03

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85	1	((die near2 die) with inspect$3) and defect with certainty	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2001/10/02 15:09
92	7	((die near2 die) with inspect$3) and defect with probability	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2001/10/02 15:11
99	8	defect near probability with reliability	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2001/10/02 15:12
106	428	defect near probability	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2001/10/02 15:14
113	15	((("382/141-151") or ("348/87,126") or ("356/237.4,237.5")).CCLS.) and (defect near probability)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2001/10/02 15:12
120	85	defect with probability same reliability	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2001/10/02 15:16
127	45	((("382/141-151") or ("348/87,126") or ("356/237.4,237.5")).CCLS.) and (defect with probability)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2001/10/02 15:16
134	30	((("382/141-151") or ("348/87,126") or ("356/237.4,237.5")).CCLS.) and (defect with probability) not (((("382/141-151") or ("348/87,126") or ("356/237.4,237.5")).CCLS.) and (defect near probability))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2001/10/02 15:28
141	8	defect near classif$6 with (probability or certainty)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2001/10/02 15:29

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